

Product Change Notification - GBNG-27TRZC226

Date:

05 May 2020

Product Category:

8-bit Microcontrollers

Affected CPNs:



Notification subject:

CCB 4032 Final Notice: Qualification of MMT as a new assembly site for AT89C51ED2-SMSUM Atmel catalog part number (CPN) available in 68L PLCC (24.2x24.2x4.4mm) package.

Notification text:

PCN Status:

Final notification

PCN Type:

Manufacturing Change

Microchip Parts Affected:

Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change:

Qualification of MMT as a new assembly site for AT89C51ED2-SMSUM Atmel catalog part number (CPN) available in 68L PLCC (24.2x24.2x4.4mm) package.

Pre Change:

Assembled at ANAP assembly site.

Post Change:

Assembled at MMT assembly site.

Pre and Post Change Summary:

	Pre Change	Post Change
	Amkor Technology	Microchip Technology
Assembly Site	Philippine (P1/P2), INC.	Thailand
	(ANAP)	(MMT)
Wire material	Au	Au
Die attach material	8361J	3280
Molding compound material	G600	G600

Impacts to Data Sheet:

None

Change Impact:

None

Reason for Change:

To improve manufacturability by qualifying MMT as a new assembly site

Change Implementation Status:

In Progress

Estimated First Ship Date:

May 30, 2020 (date code: 2022)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Time Table Summary:



	May 2020						
Workweek	19 20 21 22 23						
Qual Report Availability	Χ						
Final PCN Issue Date	X						
Estimated Implementation Date				Х			

Method to Identify Change:

Traceability code

Qualification Report:

Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History:

May 05, 2020: Issued final notification. Attached the Qualification Report Provided estimated first ship date to be on May 30, 2020.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachment(s):

PCN_GBNG-27TRZC226_Qual_Report.pdf

Please contact your local <u>Microchip sales office</u> with questions or concerns regarding this notification.

Terms and Conditions:

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If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

Affected Catalog Part Num	bers (CPN)			
AT89C51ED2-SMSUM				



QUALIFICATION REPORT SUMMARY RELIABILITY LABORATORY

PCN #: GBNG-27TRZC226

Date June 17, 2013

Qualification of MMT as a new assembly site for AT89C51ED2-SMSUM Atmel catalog part number (CPN) available in 68L PLCC (24.2x24.2x4.4mm) package.



Purpose Qualification of MMT as a new assembly site for AT89C51ED2-SMSUM Atmel

catalog part number (CPN) available in 68L PLCC (24.2x24.2x4.4mm) package.

CCB No. 1213.02 and 4032

CN BC130309

QUAL ID Q13039 Rev. A

MP CODE CEAD17W2XBXF

Part No. PIC18F6585-I/L

BDM-000295 Rev. B

Package

Bonding No.

Type 68L PLCC

Lead Frame

Paddle size 260 x 260 mils

MaterialCDA151SurfaceAg spotProcessStamped

Lead Lock No

Part Number LF-PL068-01

Die attach material

Epoxy 3280
Wire Au wire
Mold Compound G600
Plating Composition Matte Tin



Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
ALPH134800605	TMPE213299636.100	1309Q6U
ALPH134800606	TMPE213299636.100	1309Q7D
ALPH134900067	TMPE213299636.100	1310Q7U

Result	X Pass Fail
	68L PLCC assembled by MMT (ALPH) pass reliability test per QCI-39000. This

68L PLCC assembled by MMT (ALPH) pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 1 at 245°C reflow temperature per IPC/JEDEC J-STD-020D standard.

	PACKAGE QUALIFICATION REPORT						
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks	
Moisture/Reflow Sensitivity Classification Test (At MSL Level 1)	85°C/ 85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 245°C max System: Vitronics Soltec MR1243 (IPC/JEDEC J-STD-020D)	IPC/JEDE C J-STD- 020D	135	0/135	Pass		

Precondition Prior Perform Reliability Tests	Electrical Test :+85°C and -40°C System: J750	JESD22- A113	693(0)	693		Good Devices
(At MSL Level 1)	Bake 150°C, 24 hrs System: CHINEE			693		
	85°C/85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH			693		
	3x Convection-Reflow 245°C max			693		
	System: Vitronics Soltec MR1243					
	Electrical Test :+25°C and 85°C System: J750			0/693	Pass	

PACKAGE QUALIFICATION REPORT							
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks	
	Stress Condition: -65°C to +150°C, 500 Cycles System: TABAI ESPEC TSA-70H Inspection: External crack inspection all units under 40X Optical magnification Electrical Test: + 85°C	JESD22- A104	231(0)	231	Pass	Parts had been pre-conditioned at 260°C	
Temp Cycle	System: J750		201(0)	0,201	1 455	i i di inte i i et	
	Bond Strength: Wire Pull (> 4.0 grams)		15 (0)	0/15	Pass		
	Bond Shear (18.00 grams)		15 (0)	0/15	Pass		
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22- A118		231		Parts had been pre-conditioned at 260°C	
	Electrical Test: +25°C System: J750		231(0)	0/231	Pass	77 units / lot	
	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: 5.5 Volts System: HAST 6000X	JESD22- A110		231		Parts had been pre-conditioned at 260°C	
HAST	Electrical Test:+25°C and 85°C System: J750		231(0)	0/231	Pass	77 units / lot	
High Temperature	Stress Condition: Bake 175°C, 504 hrs	JESD22- A103		45		45 units	
Storage Life	System: SHEL LAB Electrical Test :+25°C and 85°C System: J750		45(0)	0/45	Pass		

PACKAGE QUALIFICATION REPORT								
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks		
Physical	Physical Dimension,	JESD22- B100/B108	30(0) Units	0/30	Pass			
Dimensions	30 units from 1 lot							
Bond Strength	Die shear (>2.5 Kaf.)	MIL-STD- 883 METHOD 2019	30 (0) Die	0/30	Pass			
	Wire Pull (> 4.0 grams)	JESD22- B116	30 (0) Wires	0/30	Pass			
Data Assembly	Bond Shear (18.00 grams)		30 (0) bonds	0/30	Pass			